













ESD

TVS

TSS

MOV

GDT

PLED

MJD42CT4G(MS)

Product specification



MSKSEMI SEMICONDUCTOR

TRANSISTOR (PNP)

FEATURES

- Designed for General Purpose Amplifier and Low Speed Switching Applications.
- Lead Formed for Surface Mount Applications in Plastic Sleeves
- Electrically Similar to Popular TIP41 and TIP42 Series
- IMonolithic Construction With Built–in Base–Emitter Resistors

Reference News

PACKAGE OUTLINE	COMPLEMENTARY	Marking
1.BASE 2.COLLECTOR 3.EMITTER	COLLECTOR 2 1 BASE 3 EMITTER	MSKSEMI MJD42CT4G MS XXX

Notes :XXX represents the order code.

MAXIMUM RATINGS (Ta=25 ℃ unless otherwise noted)

Symbol	Parameter	Value	Unit
Vсво	Collector-Base Voltage	-100	V
VCEO	Collector-EmitterVoltage	-100	V
V _{EBO}	Emitter-Base Voltage	-5	V
lc	Collector Current -Continuous	-6	А
	Collector Current -Pluse	-10	A
Pc	Collector Power Dissipation	1.25	W
TJ,Tstg	Operating Junction and Storage Temperature Range	-55-150	ĉ



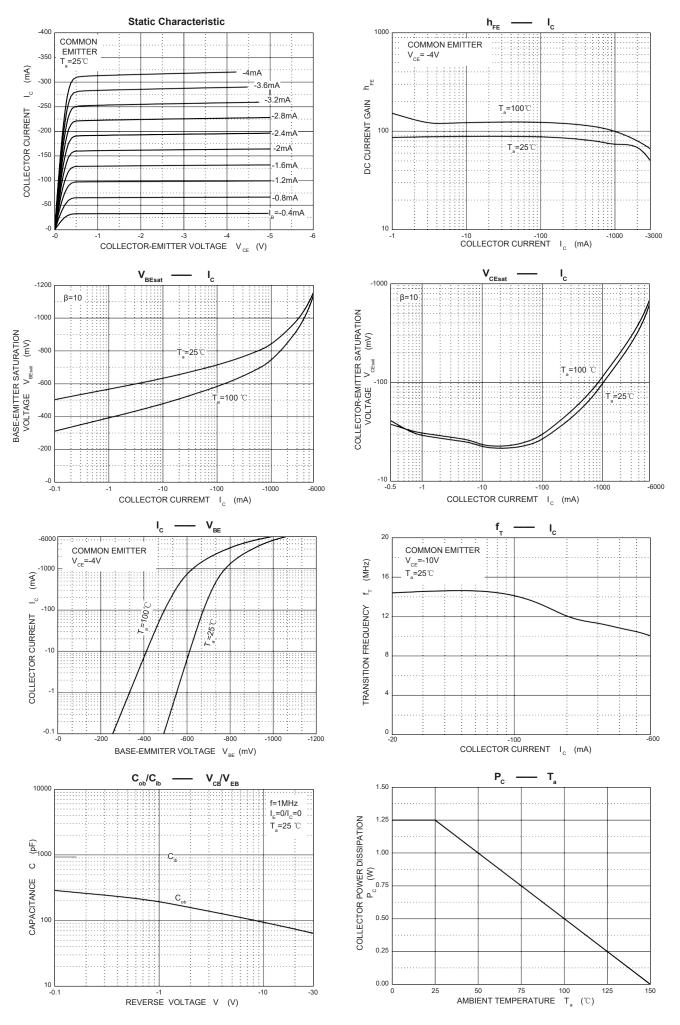
ELECTRICAL CHARACTERISTICS (Ta=25 $^\circ\!\!\mathrm{C}$ unless otherwise specified)

Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V(BR)CBO	Ι _C =-100μΑ,Ι _E =0	-100			V
Collector-emitter breakdown voltage	V _{CEO(sus)}	I _C =-30mA,I _B =0	-100			V
Emitter-base breakdown voltage	V(BR)EBO	l _E =-100μΑ,I _C =0	-5			V
Collector cut-off current	ICEO	V _{CB} =-60V,I _E =0			-50	μA
Emitter cut-off current	Іево	V _{EB} =-5V I _C =0			-0.5	mA
DC ourrent goin	h _{FE(1)}	V _{CE} =-4V I _C =-0.3A	30			
DC current gain	hFE(2)	V _{CE} =-4V,I _C =-3A	15		75	
Collector-emitter saturation voltage	V _{CE(sat)}	I _C =-6A,I _B =-0.6A			-1.5	V
Base-emitter voltage	VBE	V _{CE} =-4V,I _C =-6A			-2	V
Transition frequency	f⊤	V _{CE} =-10V,I _C =-500mA,f=1MHz	3			MHz

* Pulse Test: PW≤300µs, Duty Cycle≤2%

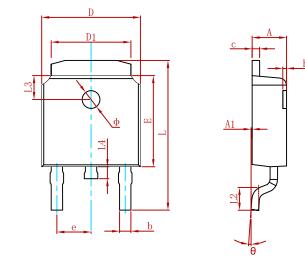


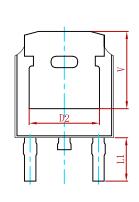
MJD42CT4G(MS)





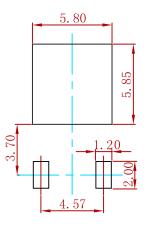
PACKAGE MECHANICAL DATA





Symbol	Dimensions	In Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
Α	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.635	0.770	0.025	0.030
С	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 REF.		0.190 REF.	
E	6.000	6.200	0.236	0.244
е	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900 REF.		0.114 REF.	
L2	1.400	1.700	0.055	0.067
L3	1.600 REF.		0.063	REF.
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250 REF.		0.207	REF.

Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm.
3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
MJD42CT4G(MS)	TO-252	2500



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